Search Notes

Application/Control No.	Applicant(s)/Pate Reexamination	Applicant(s)/Patent under Reexamination	
10/585,407	NAKATA, TSUN	ΙΕΟ	
Examiner	Art Unit		
Andrew Lee	2472		

	SEAR	CHED	
Class	Subclass	Date	Examiner
370	252,392 412,465	1/29/2011	AL

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
370	252,412	1/29/2011	AL		
370	465	1/29/2011	AL		

SEAR( (INCLUDING SE	CH NOTES EARCH STRATEGY	<b>(</b> )
	DATE	EXMR
Updated Search Inventor Search	1/29/2011	AL